



520.43279X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): S. YAMASHITA, et al

Serial No.: 10/706,972

Filed: November 14, 2003

For: **QUALITY MONITORING SYSTEM FOR BUILDING
STRUCTURE, QUALITY MONITORING METHOD FOR
BUILDING STRUCTURE AND SEMICONDUCTOR
INTEGRATED CIRCUIT DEVICE**

Group:

Examiner:

**SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98**

Mail Stop DD
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

February 20, 2004

Sir:

Further to the Information Disclosure Statement filed February 11, 2004, it is noted that the document JP 07-050104 submitted and identified as having a date of 2/95 was incorrect, and submitted herewith is a copy of JP 7-050104 having a date of 5/95 together with an English language abstract thereof, which document is properly described in the comments of the Information Disclosure Statement filed February 11, 2004.

It is respectfully requested that the information disclosure statements be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account No. 01-2135 (520.43279X00) and please credit any excess fees to such deposit account.

Respectfully submitted,



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Form PTO-1449
Equivalent

U.S. Department of Commerce
Patent and Trademark Office

Atty. Docket No. 520.43279X00
Serial No. 10/706,972
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Group:



U.S. Patent Documents

Examiner Initials	Document No.	Date	Name	Class Subclass	Filing Date If Approp.
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Foreign Patent Documents

Document No.	Date	Country	Class Subclass	Translation Yes No
7-050104	5/95	Japan		

Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

Examiner

Date Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609;
Draw line through citation if not in conformance and not considered. Include copy of this form with next
communication to applicant.